

# Optical Metrology 2008 - International Symposium on Optical Metrology in Industrial, Medical, and Daily Life Applications

Sponsored by the Optical Methods Technical Division

*Organized by: Jaime Cárdenas-García, The University of Texas at Brownsville; Cosme Furlong, Worcester Polytechnic Institute; Yu-Lung Lo, National Cheng Kung University; Ramon Rodriguez-Vera, Centro de Investigaciones en Optica*



Recent advances in imaging and computing systems, laser instrumentation, data acquisition and processing, and MEMS and Nanotechnologies are enabling the development of advanced optical metrology tools with unprecedented capabilities and a wide range of applications.

To provide a forum to discuss recent advances in optical metrology as it relates to industrial, medical, and daily life applications, the Optical Methods Technical Division of the Society for Experimental Mechanics (SEM) is pleased to organize *Optical Metrology 2008*. The aim of this Symposium is to bring practitioners and researchers from multiple disciplines to present their work in, but not limited to, the following areas:

- Fundamental Optical Metrology
- Novel Measuring Methods and Techniques
- 3D Quality Inspection and Metrology
- Intelligent Measuring Devices
- Shape and Deformation Measurements
- Interferometric and Diffractive Methods
- Metrology for Precision Measurements
- Innovative Photonic Components and Techniques
- Dimensional Measurements in Production
- Quality Management
- Fiber Optics Sensors
- Photonics Measurements in Medicine and Biology
- Measurements of Geometrical Quantities (Industrial Application of Geometrical Measurements)
- Optical and Laser Applications in Everyday Life
- Thin-film Metrology
- Trends and Future Directions in Optical Metrology
- MEMS and Nanotechnology for Optical Metrology
- Optical Methods for MEMS and Nanotechnology

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